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JC09 Rec'd PCT/PTO 02 AUG 2005

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

FUJIMOTO ET AL

National phase of International Application No. PCT/JP2004/001157

International filing date: February 4, 2004

Date of entry into national phase: August 2, 2005

For: METHOD OF INTERCONNECTING TERMINALS AND
METHOD OF MOUNTING SEMICONDUCTOR DEVICES

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Pursuant to the requirements of 37 CFR §§1.56 and 1.97, the attention of the Examiner is directed to the documents listed on the attached Form PTO-1449. A copy of each listed document is attached. Neither this Statement nor the listing of these documents on Form PTO-1449 is an admission that these documents are prior art as to the Applicants or a representation that a search has been made or that no more pertinent documents exist.

Documents AF and AI - AL were cited in the International Search Report in connection with the international phase of the

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present application. A copy of the Search Report is attached.

Documents AG, AH, AM, and AN are discussed on pages 2 - 4 of the specification of the present application.

The Applicants respectfully request that the listed documents be considered by the Examiner and made of record in the present application.

Respectfully submitted,

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Date: August 2, 2005

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Form PTO-1449 (modified) List of Patent and Publications For Applicant's Information Disclosure Statement (use several sheets if necessary)								Atty. Docket. No.:	Intl. Appln. No.:
								1076	PCT/JP2004/ 001157
								Applicant: Kozo Fujimoto et al	
Page 1 of 1								Intl. Filing Date: February 4, 2004	Art Unit:

U.S. PATENT DOCUMENTS

Exr's Initial		Document No.							Date	Name	Class	Sub class	Filing Date
	AA												
	AB												
	AC												
	AD												
	AE												

FOREIGN PATENT DOCUMENTS

		Document No.							Date	Country	Class	Sub class	Translation	
													Yes No	
	AF	08	1	8	6	1	5	6	7/16/96	JP				Abstract
	AG	08	3	1	5	8	8	3	11/29/96	JP				Abstract
	AH	10	0	0	4	1	2	6	1/6/98	JP				Abstract
	AI	11	0	0	4	0	6	4	1/6/98	JP				Abstract
	AJ	11	1	8	6	3	3	4	7/9/99	JP				Abstract
	AK	2002	0	2	6	0	7	0	1/25/02	JP				Abstract
	AL	2002	3	4	3	8	2	9	11/29/02	JP				Abstract
	AM	WO 00	5	7	4	6	9		9/28/00	WO				Abstract

OTHER ART (Including author, title, date pertinent pages, etc.)

	AN	"Study of Evaluation of Adhesive Property in Resin Joint" by Y. Ohta et al., 8th Symposium on Microjoining and Assembly Technology in Electronics, January 31 - February 1, 2002, Yokohama, Japan
	AO	
	AP	

Examiner Date considered:

EXAMINER: Initial if reference considered, no matter whether citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.